



SHEET 1 OF 1

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 211559US2SRDDIV		SERIAL NO. 09/920,936	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Toshiaki WATANABE, et al.			
				FILING DATE August 3, 2001		GROUP 2663	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
<i>Ph</i>	AA	5,162,923	11/10/92	T. YOSHIDA, et al.			
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
<i>Ph</i>	AL	04-239839	08/27/92	JAPAN (with English Abstract)			X
<i>Ph</i>	AM	04-245833	1992	JAPAN (submitting corr. EP 0 497 452 only)	<i>ABS</i>		
<i>Ph</i>	AN	0 497 452	08/05/92	EUROPE			
<i>Ph</i>	AO	01-213067	1989	JAPAN (submitting corr. US 5,162,923 only)	<i>ABS</i>		
<i>Ph</i>	AP	07-508380	1995	JAPAN (submitting corr. WO 94/00952 only)	<i>ABS</i>		
<i>Ph</i>	AQ	WO 94/00952	01/06/94	WIPO			
<i>Ph</i>	AR	07-162801	06/23/95	JAPAN (with English Abstract)			X
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
<i>Ph</i>	AS	Patent Abstracts of Japan, JP 08-162979, June 21, 1996					
<i>Ph</i>	AT	Patent Abstracts of Japan, JP 57-115043, July 17, 1982					
<i>Ph</i>	AU	Patent Abstracts of Japan, JP 02-062176, March 2, 1990					
<i>Ph</i>	AV	Patent Abstracts of Japan, JP 07-143480, June 2, 1995					
<i>Ph</i>	AW	Patent Abstracts of Japan, JP 02-206292, August 16, 1990					
<i>Ph</i>	AX	Patent Abstracts of Japan, JP 06-086251, March 25, 1994					
<i>Ph</i>	AY	Patent Abstracts of Japan, JP 06-215492, August 5, 1994					
<i>Ph</i>	AZ	Patent Abstracts of Japan, JP 06-205384, July 22, 1994					
Examiner <i>Pankaj Kumar</i>				Date Considered <i>12/2004</i>			
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

RECEIVED
APR 18 2002
Technology Center 2500

Corr:

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.